



<p style="text-align: center;"><b>Searched</b></p> 	<p>Application/Control No.</p> <p>10707647</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>TSAI ET AL.</p>
	<p>Examiner</p> <p>Kaplan, Hal I</p>	<p>Art Unit</p> <p>2836</p>

Class	SubClass	Date	Examiner
307	130	09/25/2006	HK
326	68	09/25/2006	HK
327	408	09/25/2006	HK
327	534	09/25/2006	HK

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<b>Search Notes</b>  	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10707647	TSAI ET AL.
	Examiner Kaplan, Hal I	Art Unit 2836

Notes	Date	Examiner
326/34,68,80,81 (consulted Anh Tran)	06/02/2006	HK
327/408,534 (consulted Quan Tra)	06/02/2006	HK
EAST (US-PGPUB,USPAT,USOCR,EPO,JPO,DERWENT,IBM_TDB) - See Search History Printout	09/25/2006	HK
326/34,80,81 (cursory)	06/02/2006	HK
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